

Language skills

Հայերեն English Русский Українська

Publications

Article

Analytics for AI Related Applications of Multidimensional Multitape Finite Automata

Samvel SHOUKOURIAN, Tigran GRIGORYAN, Sevak AMIRKHANYAN

Electronics, Communications and Networks 2023 49-60

Article

Functional Safety Compliant Test & Repair Framework for System-on-Chip Lifecycle Management

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

Mathematical Problems of Computer Science 2021 7-17

Article

Polynomial algorithm for equivalence problem of deterministic multitape finite automata

Samvel K. Shoukourian, Hayk A. Grigoryan

Theoretical Computer Science 2020 120-132

Article

Memory Physical Aware Multi-Level Fault Diagnosis Flow

SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

Article

Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism

S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

Article

Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications

S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 25-28

Article

Automated Flow for Test Pattern Creation for IPs in SoC

S. Shoukourian, G. Harutyunyan, D. Sargsyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 21-24

Article

An Efficient Testing Methodology for Embedded Flash Memories

S. Shoukourian, G. Harutyunyan, S. Martirosyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 422-425

Article

Security Issues in Test and Repair Infrastructure for Systems-on-Chip

S. Shoukourian, G. Harutyunyan, G. Tshagharyan

Информационно-коммуникационные технологии в науке, производстве и образовании ICIT-2017 2017 114-122

Conference

An efficient approach for memory repair by reducing the number of spares.

Vrezh Sargsyan, Valery A. Vardanian, Samvel K. Shoukourian, Yervant Zorian, Avetik Yessayan

Conference

Extending fault periodicity table for testing faults in memories under 20nm.

Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

Conference

A power based memory BIST grouping methodology.

Lusine Martirosyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

Conference

Overview study on fault modeling and test methodology development for FinFET-based memories.

Grigor Tshagharyan, Gurgen Harutyunyan, Samvel K. Shoukourian, Yervant Zorian

Conference

Securing Test Infrastructure of System-on-Chips

S. Shoukourian, G.Tshagharyan, G.Harutyunyan, Y.Zorin

Conference

Armenia: Communicating to World Community in Electronic Test and Design

Samvel Shoukourian, Yuri Shoukourian, Vladimir Sahakyan

Patent

Testing Electronic Memories Based on Fault and Test Algorithm Periodicity

S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

Patent

FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS

Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

Patent

DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES

Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian
